



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002-01

CB Certificate No.: JQAQ0002-002-T

Schedule Number: IECQ-L JQAJP 13.0002-01-S Rev No.: 3 Revision Date: 2014/12/24 Page 1 of 2

TESTD PARTS

Fixed capacitor, Fixed register, Potentiometer, Varistor, Thermistor, Connector, Relay, Switch, Printed circuit board, Semiconductor Devices, Semiconductor Integrated Circuit and Optical Component

ENVIRONMENTAL TEST

IEC 60068-2-1:2007	Cold
IEC 60068-2-2:2007	Dry heat
IEC 60068-2-11:1981	Salt mist
IEC 60068-2-14:2009	Change of temperature
IEC 60068-2-18:2000	Test R and guidance: Water
IEC 60068-2-30:2005	Damp heat, cyclic (12+12-hour cycle)
IEC 60068-2-38:2009	Composite temperature/humidity cyclic test
JIS C 60068-2-42:1993	Sulphur dioxide test for contacts and connections
JIS C 60068-2-43:1993	Hydrogen sulphide test for contacts and connections
IEC 60068-2-52:1996	Salt mist, cyclic (sodium chloride solution)
IEC 60068-2-53:2010	Tests and Guidance: Combined climatic (temperature/humidity) and dynamic (vibration/shock) tests
IEC 60068-2-60:1995	Flowing mixed gas corrosion test
IEC 60068-2-66:1994	Damp heat, steady state (unsaturated pressurized vapour)
IEC 60068-2-68:1998	Dust and sand
JIS C 60068-2-78:2004	Damp heat, steady state
JIS D 0205:1987	Test method of weatherability for automotive parts
JASO D 014-4:2014	Road vehicles -- Environmental conditions and testing for electrical and electronic equipment -- Part 4: Climatic loads
ISO 20653:2013	Road vehicles -- Degrees of protection (IP code) -- Protection of electrical equipment against foreign objects, water and access
MIL STD 202G:2002	Test method standard electronic and electrical component parts
MIL STD 883J:2014	Test method standard microcircuits

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IEC QUALITY ASSESSMENT SYSTEM (IECQ)
covering Electronic Components,
Assemblies, Related Materials and Processes
For rules and details of the IECQ visit www.iecq.org

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MECHANICAL TEST

IEC 60068-2-6:2007	Vibration (sinusoidal)
IEC 60068-2-27:2008	Shock
IEC 60068-2-31:2008	Rough handling shocks, primarily for equipment-type specimens

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